

# FDS9958-F085-VB Datasheet

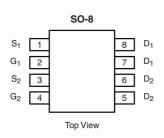
-60V Dual-P+P SOP8 Trench MOSFET

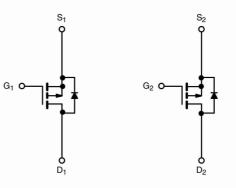
PRODUCT SUMMARY						
V <sub>DS</sub> (V)	$R_{DS(on)}$ ( $\Omega$ ) Typ.	I <sub>D</sub> (A) <sup>d</sup>	Q <sub>g</sub> (TYP.)			
-60	0.066 at V <sub>GS</sub> = -10 V	-5.0	10.1 nC			
	0.070 at V <sub>GS</sub> = -4.5 V	-4.0	10.1110			

#### **FEATURES**

- Halogen-free According to IEC 61249-2-21 Definition
- TrenchFET® Power MOSFET
- Compliant to RoHS Directive 2002/95/EC







P-Channel MOSFET

P-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (TA	SYMBOL	LIMIT	UNIT	
Drain-Source Voltage	V <sub>DS</sub>	-60		
Gate-Source Voltage		V <sub>GS</sub>	± 20	v
	T <sub>C</sub> = 25 °C		-5,0	
Continuous Dunin Comment /T 150 °C	T <sub>C</sub> = 70 °C	1 . [	-4.0	
Continuous Drain Current (T <sub>J</sub> = 150 °C)	T <sub>A</sub> = 25 °C	I <sub>D</sub>	-3.8 <sup>a,b</sup>	
	T <sub>A</sub> = 70 °C	1 [	-3.1 <sup>a,b</sup>	
Pulsed Drain Current (t = 100 μs)	I <sub>DM</sub>	-25	A	
0 11 0 0 1	T <sub>C</sub> = 25 °C		-3.9	
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	ls	-2.1 <sup>a,b</sup>	
Avalanche Current	1 . 0.1	I <sub>AS</sub>	-15	
Single-Pulse Avalanche Energy	L = 0.1 mH	E <sub>AS</sub>	11.25	mJ
	T <sub>C</sub> = 25 °C		4.2	
Mayinguna Dayyar Disaination	T <sub>C</sub> = 70 °C	1 5	2.7	w
Maximum Power Dissipation	T <sub>A</sub> = 25 °C	P <sub>D</sub>	2 a,b	VV
	T <sub>A</sub> = 70 °C		1.3 <sup>a,b</sup>	
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	-55 to 150	°C

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Marian de Ambienta	t ≤ 10 s	R <sub>thJA</sub>	53	62.5		
Maximum Junction-to-Ambient <sup>a</sup>	Steady State		85	110	°C/W	
Maximum Junction-to-Foot	Steady State	R <sub>thJF</sub>	30	37		

### Notes

- a. Surface mounted on 1" x 1" FR4 board.
- b. t = 10 s.
- c. Maximum under steady state conditions is 110  $^{\circ}\text{C/W}.$
- d. Based on  $T_C$  = 25 °C.

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PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT	
Static			<b>'</b>			'	
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> = 0 V, I <sub>D</sub> = -250 μA	-60	-	-	V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	$\frac{\Delta V_{DS}/T_{J}}{\Delta V_{GS(th)}/T_{J}}$ $I_{D} = -250 \ \mu A$		-6.7	-	mV/°C	
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$			-4.3	-		
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	-0.5	,	-2.5	V	
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$	-	-	± 100	nA	
Zara Cata Valtara Brain Current	I <sub>DSS</sub>	V <sub>DS</sub> = -60 V, V <sub>GS</sub> = 0 V	-		-1		
Zero Gate Voltage Drain Current		V <sub>DS</sub> = -60 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 55 °C	-	-	-5	μA	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge -10 \text{ V}, V_{GS} = -10 \text{ V}$	-30		-	Α	
Duain Carrier On State Besisters 3	Б	V <sub>GS</sub> = -10 V, I <sub>D</sub> = -3.5 A	-	0.066	-	Ω	
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> = -4.5 V, I <sub>D</sub> = -2.8 A	-	0.070	-		
Forward Transconductance a	9fs	$V_{DS} = -30 \text{ V}, I_D = -3.5 \text{ A}$	-	11	-	S	
Dynamic <sup>b</sup>					·		
Input Capacitance	C <sub>iss</sub>		-	832	-	pF	
Output Capacitance	C <sub>oss</sub>	$V_{DS} = -30 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	-	88	-		
Reverse Transfer Capacitance	C <sub>rss</sub>		-	63	-		
T + 1 0 - 1 - 01	Qg	$V_{DS} = -30 \text{ V}, V_{GS} = -10 \text{ V}, I_D = -3.5 \text{ A}$	- 20	20	30	nC	
Total Gate Charge			-	10.1	15.2		
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS} = -30 \text{ V}, V_{GS} = -4.5 \text{ V}, I_{D} = -3.5 \text{ A}$	-	3.3	-		
Gate-Drain Charge	$Q_{gd}$		-	3.9	-		
Gate Resistance	Rg	f = 1 MHz	1.8	9	18	Ω	
Turn-On Delay Time	t <sub>d(on)</sub>		-	8	16		
Rise Time	t <sub>r</sub>	$V_{DD} = -30 \text{ V}, R_L = 10.7 \Omega$	-	6	12		
Turn-Off DelayTime	t <sub>d(off)</sub>	$I_D \cong -2.8 \text{ A}, V_{GEN} = -10 \text{ V}, R_g = 1 \Omega$	-	35	53	1	
Fall Time	t <sub>f</sub>		-	16	24	]	
Turn-On Delay Time	t <sub>d(on)</sub>		-	40	60	ns	
Rise Time	t <sub>r</sub>	$V_{DD} = -30 \text{ V}, R_L = 10.7 \Omega$	-	28	42		
Turn-Off DelayTime	t <sub>d(off)</sub>	$I_D \cong -2.8 \text{ A}, V_{GEN} = -4.5 \text{ V}, R_g = 1 \Omega$	-	31	47		
Fall Time	t <sub>f</sub>		-	15	23		
Drain-Source Body Diode Characterist	ics				,		
Continous Source-Drain Diode Current	Is	T <sub>C</sub> = 25 °C	-	-	-3.5		
Pulse Diode Forward Current (t = 100 μs)	I <sub>SM</sub>		-	-	-20	A	
Body Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> = -2.8 A, V <sub>GS</sub> = 0 V	-	-0.85	-1.2	٧	
Body Diode Reverse Recovery Time	t <sub>rr</sub>		-	32	48	ns	
Body Diode Reverse Recovery Charge			-	45	68	nC	
Reverse Recovery Fall Time	ta	T <sub>J</sub> = 25 °C	-	24	-	See at	
Reverse Recovery Rise Time		t <sub>b</sub>		8	-	ns	

- a. Pulse test; pulse width ≤ 300 µs, duty cycle ≤ 2 %.
  b. Guaranteed by design, not subject to production testing.

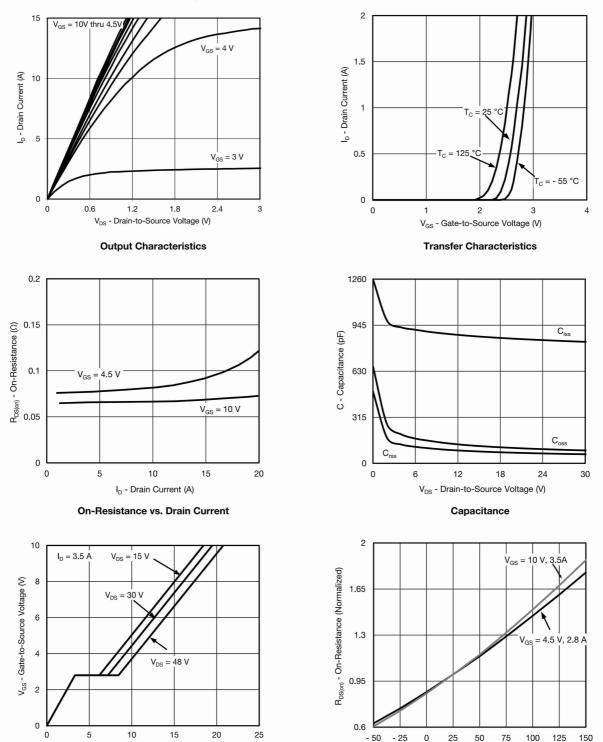
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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Q<sub>g</sub> - Total Gate Charge (nC)

Gate Charge

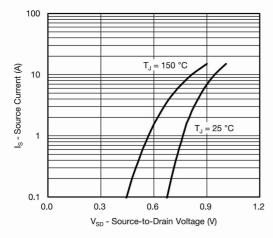


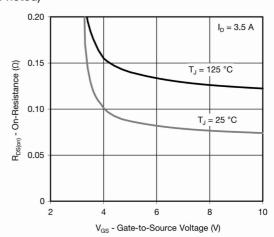
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 $T_{\text{J}}$  - Junction Temperature (°C)

On-Resistance vs. Junction Temperature

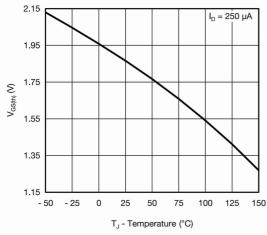


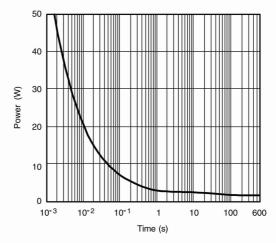




#### Source-Drain Diode Forward Voltage

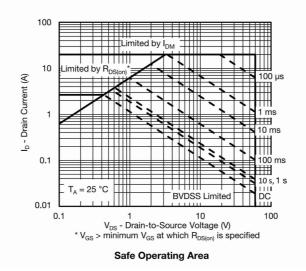




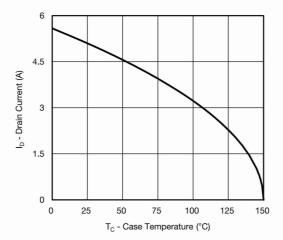


# Threshold Voltage

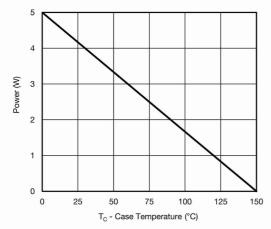
Single Pulse Power, Junction-to-Ambient

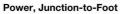


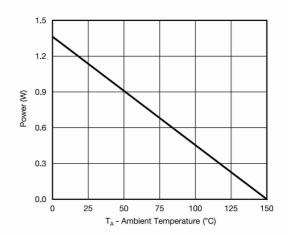




#### **Current Derating\***



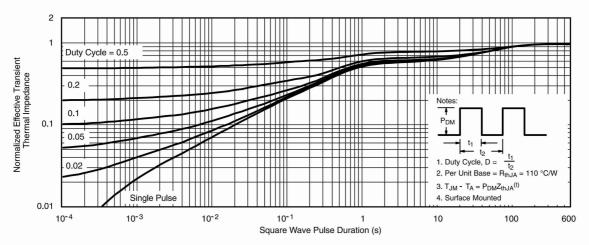




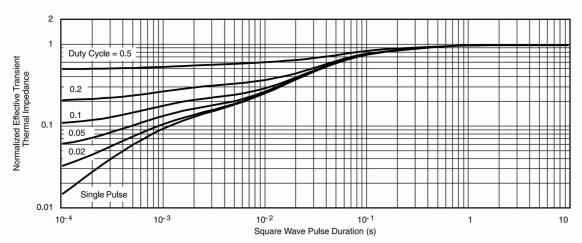
Power Derating, Junction-to-Ambient

 $<sup>^*</sup>$  The power dissipation P<sub>D</sub> is based on T<sub>J (max.)</sub> = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





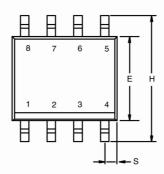
#### Normalized Thermal Transient Impedance, Junction-to-Ambient

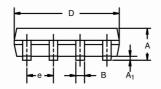


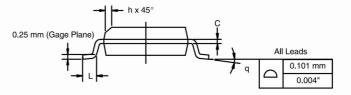
Normalized Thermal Transient Impedance, Junction-to-Foot



SOIC (NARROW): 8-LEAD JEDEC Part Number: MS-012



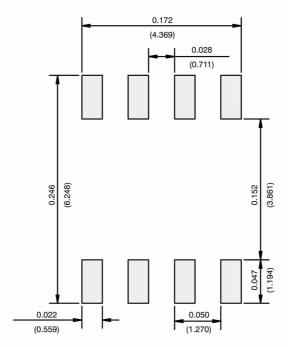




	MILLIN	IETERS	INCHES		
DIM	Min	Max	Min	Max	
Α	1.35	1.75	0.053	0.069	
A <sub>1</sub>	0.10	0.20	0.004	0.008	
В	0.35	0.51	0.014	0.020	
С	0.19	0.25	0.0075	0.010	
D	4.80	5.00	0.189	0.196	
E	3.80	4.00	0.150	0.157	
е	1.27 BSC		0.050 BSC		
Н	5.80	6.20	0.228	0.244	
h	0.25	0.50	0.010	0.020	
L	0.50	0.93	0.020	0.037	
q	0°	8°	0°	8°	
S	0.44	0.64	0.018	0.026	
ECN: C-06527-Rev. I, 11-Sep-06 DWG: 5498					



# **RECOMMENDED MINIMUM PADS FOR SO-8**



Recommended Minimum Pads Dimensions in Inches/(mm)



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